


<b>Search Notes</b>  	<b>Application/Control No.</b>  10526565	<b>Applicant(s)/Patent Under Reexamination</b>  NAGHIAN, SIAMAK
	<b>Examiner</b>  Pablo N Tran	<b>Art Unit</b>  2618

SEARCHED			
Class	Subclass	Date	Examiner
370	255, 229-230, 235, 238, 252-256, 310.1-313, 328, 338, 386-393, 432	5/10/10	PT
455	403, 418-425, 432.1, 434-445, 450-456.1	5/10/10	PT

SEARCH NOTES		
Search Notes	Date	Examiner
East/West	5/10/10	PT

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

	/P. N. T./ Primary Examiner.Art Unit 2618
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